# EE-677: Foundation of CAD for VLSI

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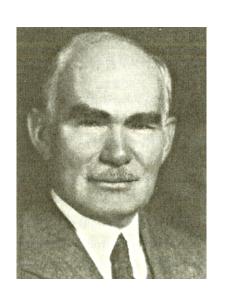
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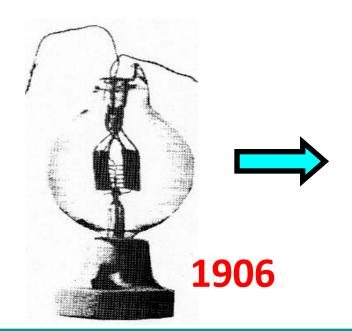
#### **History of Electronics**

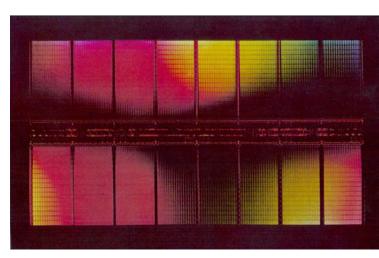
- Electronics is the most important invention in the 20<sup>th</sup> cent.
- Electronic Circuits in 100 years

Vacuum tube  $\rightarrow$  VLSI

#### 12 yeas ago, it was the 100 year anniversary

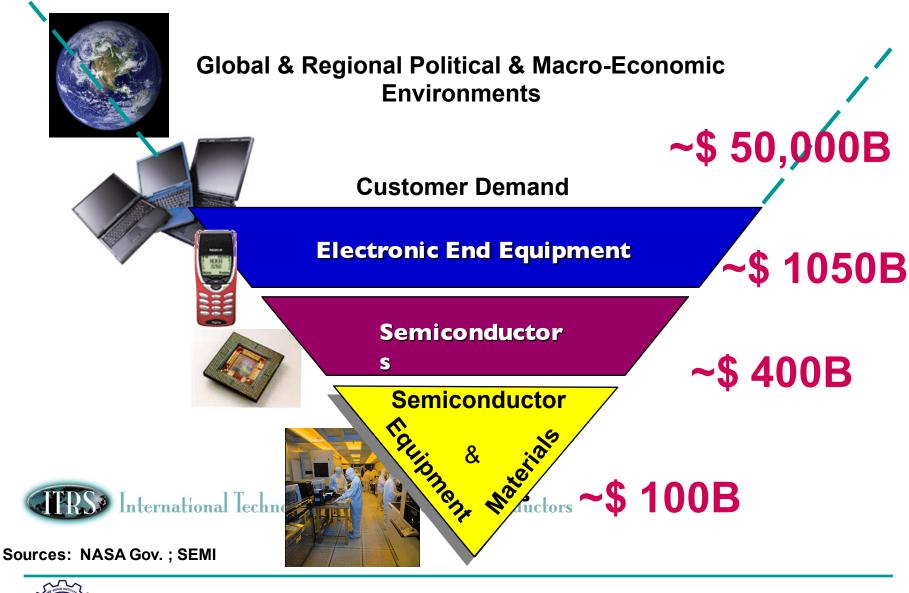








#### Wanted: CUSTOMERS, who breathe, eat, and live in.....







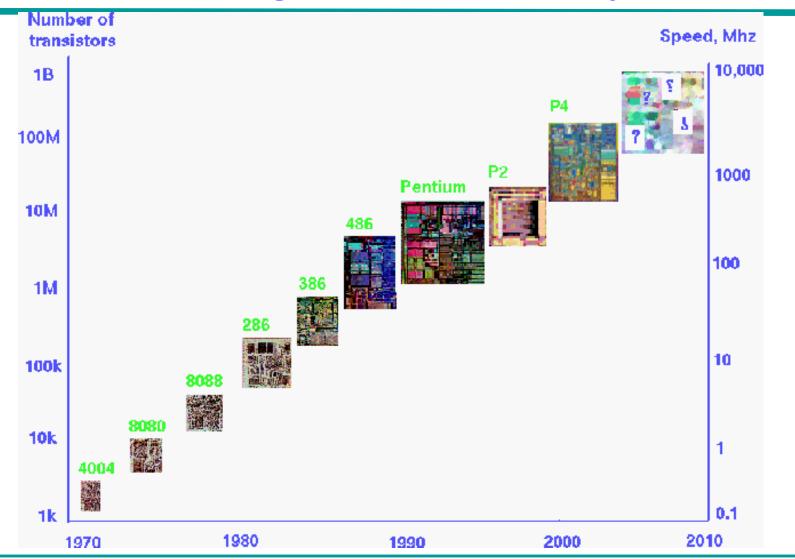
# Motivation: Moore's Law Complexity Growth of VLSI circuits

Moore's Law (1959/1.5, Sources: Intel, IBM, TI, Polsson) 1e+14 X 1 MHz 10 MHz 100 MHz 1 GHz P-III 0.18 um 1e+12 Fransistor Count per Die [-] 1e+10 i386 Copper 1e+08 O Aluminium VLIW 4004 Moore's Law (1.5) 1e+06 RISC Superscalar 10000 BJT **CMOS BiCMOS** 100 1970 1980 1990 2000 2010 2020 Source (Copp, Int. AOC EW Conf., 2002)





## **Design Complexity**







#### **VLSI** Realization Process

Customer's need

**Determine requirements** 

Write specifications

**Design synthesis and Verification** 

Test development

**Fabrication** 

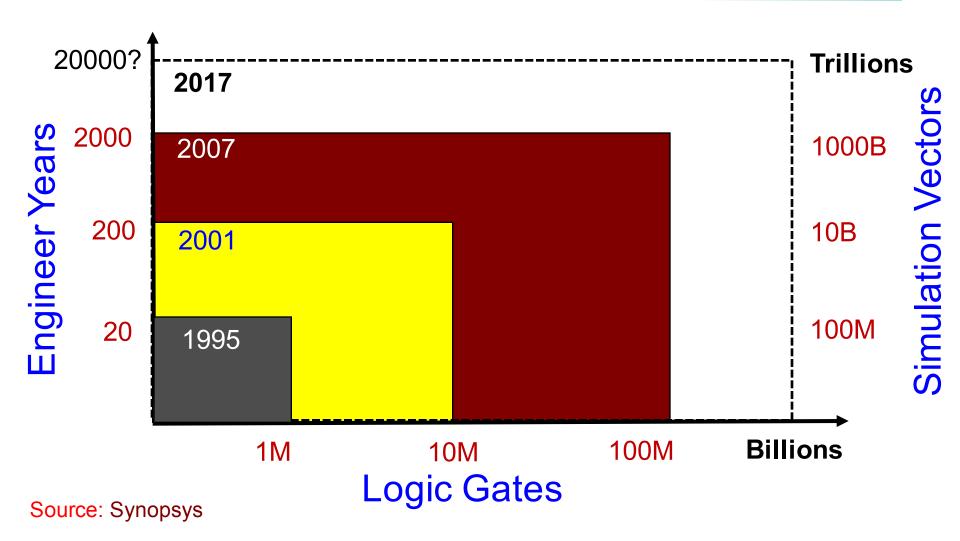
Manufacturing test

Chips to customer





#### **Design Validation Complexity**





**CADSL** 

## **Conventional SoC Design Flow**

**Bug Fix** 

Bug Localization

Verification/Sim ulation

Pre-Silicon RTL Verification

High-Level Description

High-Level Synthesis

Machine-Generated RTL

**Logic Synthesis Place & Route** 

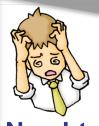
SoC (Social Control Co

Design

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75% of the whole development time [Source: Intel 2007]

Respin



Need to Understand RTL **Bug Fix** 

Bug Localization

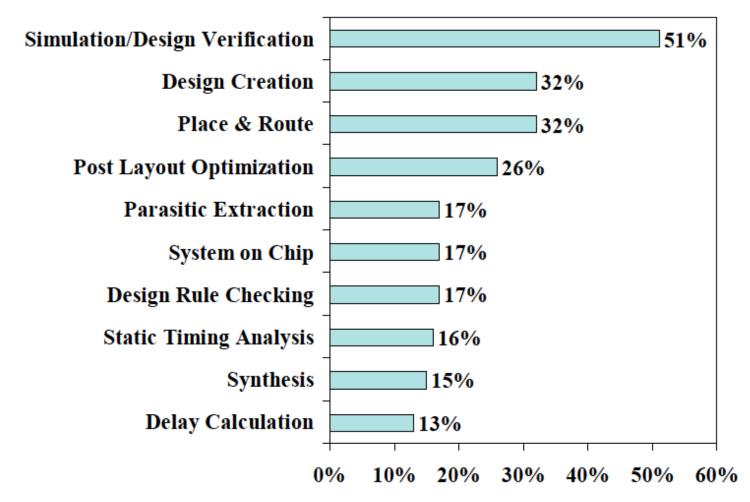
Error Detection

Post-Silicon RTL Validation





#### Verification challenge

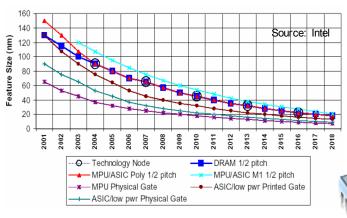


Bottlenecks in Design Cycles: Survey of 545 engineers by EETIMES 2000

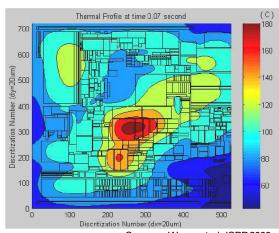




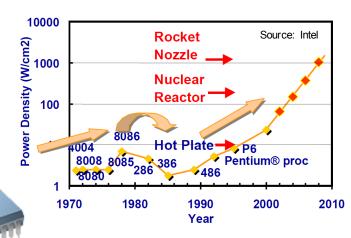
# Challenges under deep submicron technologies



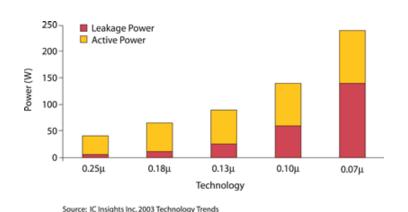
Chip size decreases



Source: Wang et al. ISPD2003
Chip becomes hotter



Power density increases



Leakage power make it worse





## Coping with Complexity

- How to design System-on-Chip?
  - Billions of transistors
  - Tens to hundreds of engineers
- Structured Design
- Design Partitioning



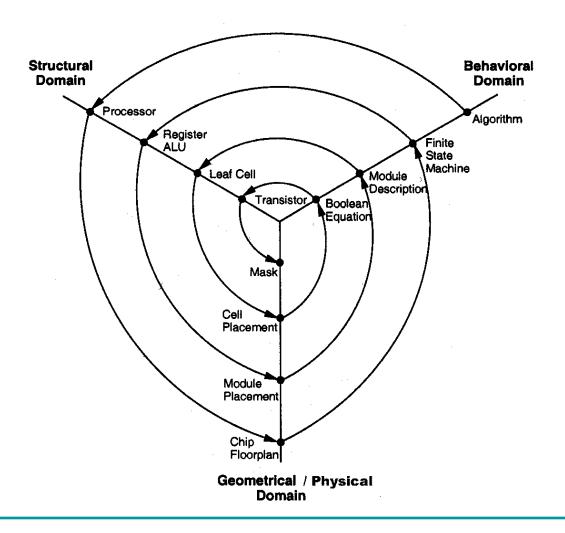
#### Structured Design

- Hierarchy: Divide and Conquer
  - Recursively system into modules
- Regularity
  - Reuse modules wherever possible
  - Ex: Standard cell library
- Modularity: well-formed interfaces
  - Allows modules to be treated as black boxes
- Locality
  - Physical and temporal





#### Gajski Y-Chart





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#### **Definitions**

- Design synthesis: Given an I/O function, develop a procedure to manufacture a device using known materials and processes.
- Verification: Predictive analysis to ensure that the synthesized design, when manufactured, will perform the given I/O function.
- Test: A manufacturing step that ensures that the physical device, manufactured from the synthesized design, has no manufacturing defect.





#### Course Outline

- VLSI Design Flow
- High Level Synthesis
- Logic Synthesis
- Physical Design
- Hardware Software Co-design [if time permits]
- Reversible Circuit Design [if time permits]





#### Course Schedule

Class Hours: Slot 13

Monday (7:00 pm to 8:30 pm)

Tuesday (7:00 pm to 8:30 pm)

Office Hours

TBD





#### **Course Evaluation**

- Mid Term Exam (10%)
  - Open Book/Notes Exam
- Final Exam (25%)
  - Open Book/Notes Exam
- Assignments (15%)
  - Set of assignments will be given periodically
- Course Projects (20%)
  - Projects to implement CAD algorithm
- Continuous Evaluations (25%)
  - Weekly (THursday) tests (90% best will be counted)
- Presentation/Viva (5%)
- [Bonus] Research Project (15%)
- > [Bonus] Course notes (5%)





#### **Grades**

#### **Absolute Grade**

- > 90: AA
- 81 90: AB
- 71 80: BB
- 61 70: BC
- 51 60: CC
- 45 50: CD
- 40 44: DD
- < 40 : FR



## **Books (Design Verification)**

- Synthesis and Optimization of Digital Circuits
  - Giovanni De Michelli
- Logic Synthesis and Verification
  - Hatchel & Somanzi
- Algorithm for Physical Design Automation
  - Naveed Shervani
- Current Literature (IEEE TC/TCAD/TVLSI)





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# Thank You



